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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	125
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-1pqg160m

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f_{q2} = Average second routed array clock rate in MHz)

Table 7 • Fixed Capacitance Values for MX FPGAs (pF)

Device Type	r1 routed_Clk1	r2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

3.4.6 Test Circuitry and Silicon Explorer II Probe

MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 12, page 16 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 13, page 17 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (See User Security, page 12 for the security fuses of 40MX and 42MX devices). Table 8, page 17 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the "Reserve Probe Pin" is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and "Reserve Probe Pin" is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

Figure 12 • Silicon Explorer II Setup with 40MX

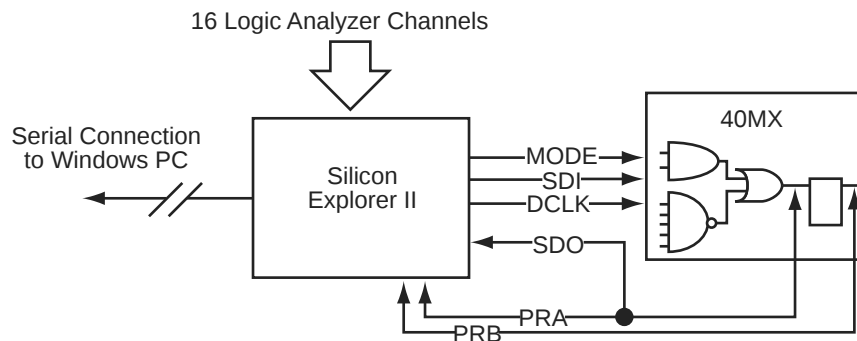
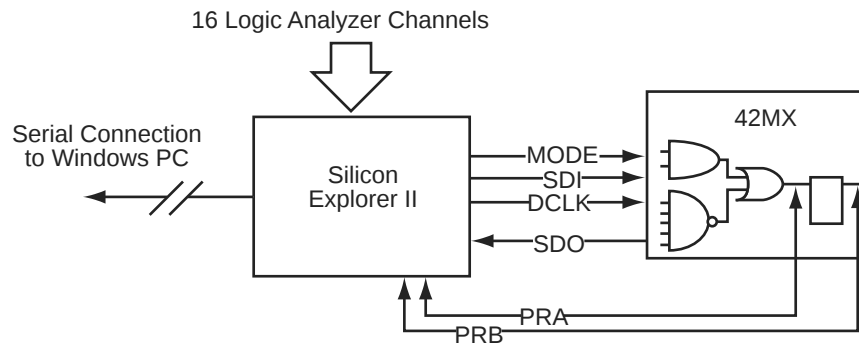


Figure 13 • Silicon Explorer II Setup with 42MX**Table 8 • Device Configuration Options for Probe Capability**

Security Fuse(s) Programmed	Mode	PRA, PRB ¹	SDI, SDO, DCLK ¹
No	LOW	User I/Os ²	User I/Os ²
No	HIGH	Probe Circuit Outputs	Probe Circuit Inputs
Yes	–	Probe Circuit Secured	Probe Circuit Secured

1. Avoid using SDI, SDO, DCLK, PRA and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
2. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. See the Pin Descriptions, page 83 for information on unused I/O pins

3.4.7 Design Consideration

It is recommended to use a series 70 Ω termination resistor on every probe connector (SDI, SDO, MODE, DCLK, PRA and PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

3.4.8 IEEE Standard 1149.1 Boundary Scan Test (BST) Circuitry

42MX24 and 42MX36 devices are compatible with IEEE Standard 1149.1 (informally known as Joint Testing Action Group Standard or JTAG), which defines a set of hardware architecture and mechanisms for cost-effective board-level testing. The basic MX boundary-scan logic circuit is composed of the TAP (test access port), TAP controller, test data registers and instruction register (Figure 14, page 18). This circuit supports all mandatory IEEE 1149.1 instructions (EXTEST, SAMPLE/PRELOAD and BYPASS) and some optional instructions. Table 9, page 18 describes the ports that control JTAG testing, while Table 10, page 18 describes the test instructions supported by these MX devices.

Each test section is accessed through the TAP, which has four associated pins: TCK (test clock input), TDI and TDO (test data input and output), and TMS (test mode selector).

The TAP controller is a four-bit state machine. The '1's and '0's represent the values that must be present at TMS at a rising edge of TCK for the given state transition to occur. IR and DR indicate that the instruction register or the data register is operating in that state.

The TAP controller receives two control inputs (TMS and TCK) and generates control and clock signals for the rest of the test logic architecture. On power-up, the TAP controller enters the Test-Logic-Reset state. To guarantee a reset of the controller from any of the possible states, TMS must remain high for five TCK cycles.

42MX24 and 42MX36 devices support three types of test data registers: bypass, device identification, and boundary scan. The bypass register is selected when no other register needs to be accessed in a device. This speeds up test data transfer to other devices in a test data path. The 32-bit device identification register is a shift register with four fields (lowest significant byte (LSB), ID number, part number and version). The boundary-scan register observes and controls the state of each I/O pin.

Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Microsemi's integrated verification and logic analysis tool. Another tool included in the Libero software is the SmartGen macro builder, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design.

Microsemi's Libero software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synopsys, and Cadence design systems.

See the Libero IDE web content at www.microsemi.com/soc/products/software/libero/default.aspx for further information on licensing and current operating system support.

3.6 Related Documents

The following sections give the list of related documents which can be referred for this datasheet.

3.6.1 Application Notes

- *AC278: BSDL Files Format Description*
- *AC225: Programming Antifuse Devices*
- *AC168: Implementation of Security in Microsemi Antifuse FPGAs*

3.6.2 User Guides and Manuals

- *Antifuse Macro Library Guide*
- *Silicon Sculptor Programmers User Guide*

3.6.3 Miscellaneous

Libero IDE Flow Diagram

3.7 5.0 V Operating Conditions

The following tables show 5.0 V operating conditions.

Table 12 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCC+0.5	V
VO	Output Voltage	–0.5 to VCC+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 13 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	–0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCCI+0.5	V
VO	Output Voltage	–0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

3.8.1 3.3 V LVTTTL Electrical Specifications

Table 19 • 3.3V LVTTTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = -4 mA	2.15		2.15		2.4		2.4		V
VOL ¹	IOL = 6 mA		0.4		0.4		0.48		0.48	V
VIL		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX)		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL			-10		-10		-10		-10	μA
IIH			-10		-10		-10		-10	μA
Input Transition Time, T _R and T _F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ²	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		15		25		25		25	mA
Low-Power Mode Standby Current	42MX devices only		0.5		ICC - 5.0		ICC - 5.0		ICC - 5.0	mA
I/O, I/O source sink current	Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min.
2. All outputs unloaded. All inputs = VCC/VCCI or GND.

3.9 Mixed 5.0 V / 3.3 V Operating Conditions (for 42MX Devices Only)

Table 20 • Absolute Maximum Ratings*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	-0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCCA + 0.5	V
VO	Output Voltage	-0.5 to VCCI + 0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device

reliability. Devices should not be operated outside the recommended operating conditions.

Table 21 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCCA	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI	3.14 to 3.47	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PWL}	Minimum Pulse Width LOW	FO = 32	3.2		3.5		4.0		4.7		6.6		ns
		FO = 384	3.7		4.1		4.6		5.4		7.6		ns
t _{CKSW}	Maximum Skew	FO = 32		0.3		0.4		0.4		0.5		0.7	ns
		FO = 384		0.3		0.4		0.4		0.5		0.7	ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 384	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		5.5		4.1		5.7		ns
		FO = 384	3.2		3.5		4.0		4.7		6.6		ns
t _P	Minimum Period	FO = 32	4.2		4.67		5.1		5.8		9.7		ns
		FO = 384	4.6		5.1		5.6		6.4		10.7		ns
f _{MAX}	Maximum Frequency	FO = 32		237		215		198		172		103	MHz
		FO = 384		215		195		179		156		94	MHz

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.2		3.6		4.0		4.7		6.6	ns
t _{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t _{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.4		4.0		5.6	ns
t _{ENZL}	Enable Pad Z to LOW		3.0		3.3		3.8		4.4		6.2	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.4		6.0		6.8		8.0		11.2	ns
t _{ENLZ}	Enable Pad LOW to Z		5.0		5.6		6.3		7.4		10.4	ns
t _{GLH}	G-to-Pad HIGH		5.1		5.6		6.4		7.5		10.5	ns
t _{GHL}	G-to-Pad LOW		5.1		5.6		6.4		7.5		10.5	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.7		6.3		7.1		8.4		11.9	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0		8.9		10.1		11.9		16.7	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, point and position whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays ¹												
t _{PD1}	Single Module		1.9		2.1		2.4		2.8		4.0	ns
t _{CO}	Sequential Clock-to-Q		2.0		2.2		2.5		3.0		4.2	ns
t _{GO}	Latch G-to-Q		1.9		2.1		2.4		2.8		4.0	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		2.2		2.4		2.8		3.3		4.6	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		1.1		1.2		1.4		1.6		2.3	ns
t _{RD2}	FO = 2 Routing Delay		1.5		1.6		1.8		2.1		3.0	ns
t _{RD3}	FO = 3 Routing Delay		1.8		2.0		2.3		2.7		3.8	ns
t _{RD4}	FO = 4 Routing Delay		2.2		2.4		2.7		3.2		4.5	ns
t _{RD8}	FO = 8 Routing Delay		3.6		4.0		4.5		5.3		7.5	ns

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.1		3.5		3.9		4.6		6.4	ns
t _{DHL}	Data-to-Pad LOW		2.4		2.6		3.0		3.5		4.9	ns
t _{ENZH}	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3	ns
t _{ENZL}	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.8	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7	ns
t _{ENLZ}	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9	ns
t _{GLH}	G-to-Pad HIGH		4.9		5.4		6.2		7.2		10.1	ns
t _{GHL}	G-to-Pad LOW		4.9		5.4		6.2		7.2		10.1	ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.5		6.1		6.9		8.1		11.3	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading

Table 43 • A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay		2.0		1.8		2.1		2.5		3.4	ns
t _{PDD}	Internal Decode Module Delay		1.1		2.2		2.5		3.0		4.2	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		1.7		1.3		1.4		1.7		2.3	ns
t _{RD2}	FO = 2 Routing Delay		2.0		1.6		1.8		2.1		3.0	ns
t _{RD3}	FO = 3 Routing Delay		1.1		2.0		2.2		2.6		3.7	ns
t _{RD4}	FO = 4 Routing Delay		1.5		2.3		2.6		3.1		4.3	ns
t _{RD5}	FO = 8 Routing Delay		1.8		3.7		4.2		5.0		7.0	ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Synchronous SRAM Operations (continued)												
t _{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RENSU}	Read Enable Set-Up	0.9		1.0		1.1		1.3		1.8		ns
t _{RENH}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t _{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t _{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{BENS}	Block Enable Set-Up	3.9		4.3		4.9		5.7		8.0		ns
t _{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
Asynchronous SRAM Operations												
t _{RPD}	Asynchronous Access Time		11.3		12.6		14.3		16.8		23.5	ns
t _{RDADV}	Read Address Valid	12.3		13.7		15.5		18.2		25.5		ns
t _{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns
t _{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RENSUA}	Read Enable Set-Up to Address Valid	0.9		1.0		1.1		1.3		1.8		ns
t _{RENHA}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t _{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t _{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{DOH}	Data Out Hold Time		1.8		2.0		2.1		2.5		3.5	ns
Input Module Propagation Delays												
t _{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.1		3.0	ns
t _{INGO}	Input Latch Gate-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t _{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10k Ω pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Figure 39 • PL68

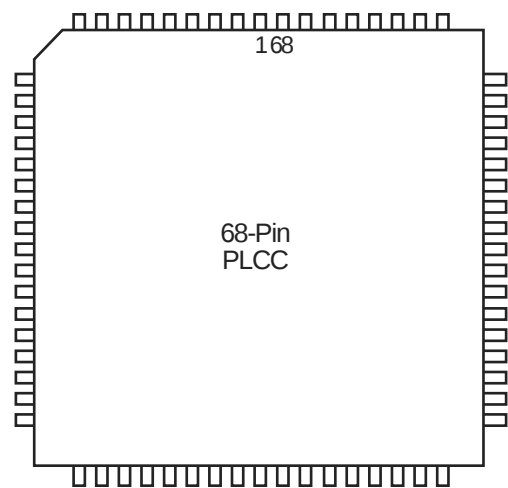


Table 48 • PL68

PL68		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	I/O	I/O
3	I/O	I/O
4	VCC	VCC
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	GND	GND
15	GND	GND
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O
21	VCC	VCC
22	I/O	I/O
23	I/O	I/O

Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
117	GNDI
118	NC
119	I/O
120	I/O
121	I/O
122	I/O
123	PROBA
124	I/O
125	CLKA
126	VCC
127	VCCI
128	NC
129	I/O
130	CLKB
131	I/O
132	PROBB
133	I/O
134	I/O
135	I/O
136	GND
137	GNDI
138	NC
139	I/O
140	I/O
141	I/O
142	I/O
143	I/O
144	DCLK

Table 52 • PQ160

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
95	I/O	I/O	I/O
96	I/O	I/O	WD, I/O
97	I/O	I/O	I/O
98	VCCA	VCCA	VCCA
99	GND	GND	GND
100	NC	I/O	I/O
101	I/O	I/O	I/O
102	I/O	I/O	I/O
103	NC	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	I/O	I/O	WD, I/O
107	I/O	I/O	WD, I/O
108	I/O	I/O	I/O
109	GND	GND	GND
110	NC	I/O	I/O
111	I/O	I/O	WD, I/O
112	I/O	I/O	WD, I/O
113	I/O	I/O	I/O
114	NC	VCCI	VCCI
115	I/O	I/O	WD, I/O
116	NC	I/O	WD, I/O
117	I/O	I/O	I/O
118	I/O	I/O	TDI, I/O
119	I/O	I/O	TMS, I/O
120	GND	GND	GND
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	NC	I/O	I/O
125	GND	GND	GND
126	I/O	I/O	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	NC	I/O	I/O
130	GND	GND	GND
131	I/O	I/O	I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
95	NC	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	VCCI	VCCI	VCCI
99	I/O	I/O	I/O
100	I/O	WD, I/O	WD, I/O
101	I/O	WD, I/O	WD, I/O
102	I/O	I/O	I/O
103	SDO, I/O	SDO, TDO, I/O	SDO, TDO, I/O
104	I/O	I/O	I/O
105	GND	GND	GND
106	NC	VCCA	VCCA
107	I/O	I/O	I/O
108	I/O	I/O	I/O
109	I/O	I/O	I/O
110	I/O	I/O	I/O
111	I/O	I/O	I/O
112	NC	I/O	I/O
113	NC	I/O	I/O
114	NC	I/O	I/O
115	NC	I/O	I/O
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	I/O	I/O	I/O
126	GND	GND	GND
127	I/O	I/O	I/O
128	I/O	TCK, I/O	TCK, I/O
129	LP	LP	LP
130	VCCA	VCCA	VCCA
131	GND	GND	GND

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
121	NC	NC	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	NC	I/O	I/O
125	NC	I/O	I/O
126	NC	NC	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	I/O	I/O	I/O
130	I/O	I/O	I/O
131	I/O	I/O	I/O
132	I/O	I/O	I/O
133	GND	GND	GND
134	I/O	I/O	I/O
135	SDI, I/O	SDI, I/O	SDI, I/O
136	NC	I/O	I/O
137	I/O	I/O	WD, I/O
138	I/O	I/O	WD, I/O
139	I/O	I/O	I/O
140	NC	VCCI	VCCI
141	I/O	I/O	I/O
142	I/O	I/O	I/O
143	NC	I/O	I/O
144	NC	I/O	WD, I/O
145	NC	NC	WD, I/O
146	I/O	I/O	I/O
147	NC	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	I/O	I/O	WD, I/O
151	NC	I/O	WD, I/O
152	PRA, I/O	PRA, I/O	PRA, I/O
153	I/O	I/O	I/O
154	CLKA, I/O	CLKA, I/O	CLKA, I/O
155	VCCA	VCCA	VCCA
156	GND	GND	GND
157	I/O	I/O	I/O

Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	I/O
117	I/O
118	I/O
119	I/O
120	I/O
121	I/O
122	I/O
123	I/O
124	I/O
125	I/O
126	GND
127	I/O
128	TCK, I/O
129	LP
130	VCCA
131	GND
132	VCCI
133	VCCA
134	I/O
135	I/O
136	VCCA
137	I/O
138	I/O
139	I/O
140	I/O
141	I/O
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
J9	GND
J10	GND
J11	GND
J12	GND
J17	VCCA
J18	I/O
J19	I/O
J20	I/O
K1	I/O
K2	I/O
K3	I/O
K4	VCCI
K9	GND
K10	GND
K11	GND
K12	GND
K17	I/O
K18	VCCA
K19	VCCA
K20	LP
L1	I/O
L2	I/O
L3	VCCA
L4	VCCA
L9	GND
L10	GND
L11	GND
L12	GND
L17	VCCI
L18	I/O
L19	I/O
L20	TCK, I/O
M1	I/O
M2	I/O
M3	I/O
M4	VCCI
M9	GND

Table 61 • PG132

PG132	
Pin Number	A42MX09 Function
B3	I/O
A2	I/O
C3	DCLK
B5	GND A
E12	GND A
J2	GND A
M9	GND A
B9	GND I
C5	GND I
E11	GND I
F4	GND I
J3	GND I
J11	GND I
L5	GND I
L9	GND I
C9	GND Q
E3	GND Q
K12	GND Q
D7	VCCA
G3	VCCA
G10	VCCA
L7	VCCA
C7	VCCI
G2	VCCI
G11	VCCI
K7	VCCI